

The width of a uniform distribution: estimation in additive error models

M. Benšić¹ K. Sabo¹ S. Hamedović²

¹Department of Mathematics
University of Osijek

²Faculty of Metallurgy and Technology
University of Zenica

This work is supported by the Croatian Science Foundation through the research grant IP-2016-06-6545.

ISCCRO'18, Opatija, May 2018

$$X = Y + \varepsilon$$

- Typical assumptions
 - Y and ε are independent
 - error variable ε has a known PDF f_ε
 - an i.i.d. sample (X_1, X_2, \dots, X_n) on X is available
- The goal: to estimate the unknown density f_Y
- Deconvolution: non-parametric methods

$$X = Y + \varepsilon$$

- Technique of characteristic functions

$$\phi_X(t) = \phi_Y(t)\phi_\varepsilon(t)$$

- Rough scheme

- estimate $\phi_X(t)$ by an empirical version $\hat{\phi}_X(t)$
- get estimate of $\phi_Y(t)$ as $\hat{\phi}_Y(t) = \frac{\hat{\phi}_X(t)}{\phi_\varepsilon(t)}$
- regularize $\hat{\phi}_Y(t)$ before applying inversion and get $\hat{f}_Y(x)$

- Deconvolution kernel density estimator

$$X = U + \sigma\varepsilon, \quad U \sim \mathcal{U}[-a, a], \quad a > 0, \sigma > 0$$

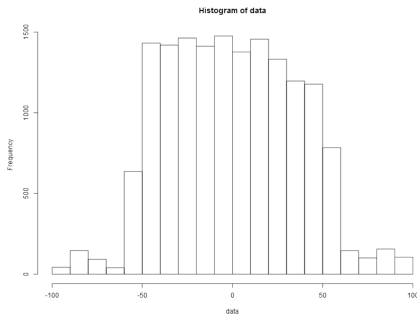
$$f_U(x) = \frac{1}{2a} I_{[-a, a]}(x),$$

- ε symmetric absolutely continuous with CDF F and PDF f
- PDF of X (convolution of f_U and $f_{\sigma\varepsilon}$):

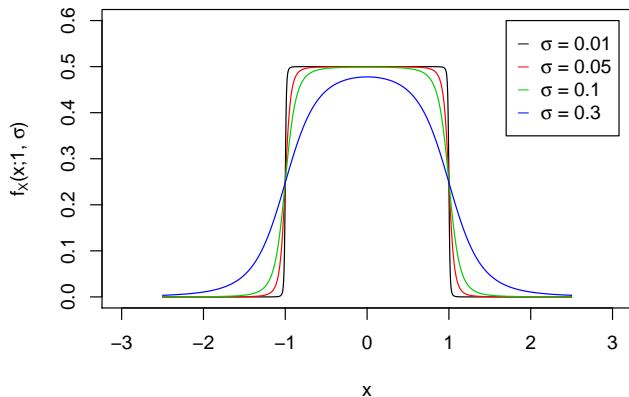
$$f_X(x; a, \sigma) = \frac{1}{2a} \left(F\left(\frac{x+a}{\sigma}\right) - F\left(\frac{x-a}{\sigma}\right) \right)$$

- To estimate:
 - a (half-length of the uniform support)
 - σ





- Estimating the size of an object from a noisy image
- Example, a medical (RTG) image







- PDF of $X = U + \varepsilon$, $U \sim \mathcal{U}[-1, 1]$, $\varepsilon \sim t_3(0, \sigma)$



Some references (1)

-  Schneeweiss, H. (2004). Estimating the endpoint of a uniform distribution under measurement errors. CEJOR 12, 221–231.
-  Benšić, M., Sabo, K. (2007). Estimating the width of a uniform distribution when data are measured with additive normal errors with known variance, Computational Statistics and Data Analysis, 51, 4731–4741
-  Benšić, M., Sabo, K. (2007). Border Estimation of a Two-dimensional Uniform Distribution if Data are Measured with Additive Error, Statistics - A Journal of Theoretical and Applied Statistics, 41, 311–319
-  Sabo K., Benšić, M.(2009). Border estimation of a disc observed with random errors solved in two steps, Journal of Computational and Applied Mathematics, 229, 16–26.

Some references (2)

-  Benšić, M., Sabo, K. (2010). Estimating a uniform distribution when data are measured with a normal additive error with unknown variance, *Statistics - A Journal of Theoretical and Applied Statistics*, 44, 235–246
-  Benšić, M., Sabo, K. (2016). Uniform distribution width estimation from data observed with Laplace additive error, *Journal of the Korean Statistical Society*
-  Benšić, M., Taler, P., Hamedović, S., Nyarko, E.K., Sabo, K. (2017). LeArEst: Length and Area Estimation from Data Measured with Additive Error, *The R Journal*, 9:2, pages 461-473.
-  Hamedović, S., Benšić, M., Sabo, K., Taler, P. (2017). Estimating the size of an object captured with error, *CEJOR*,

- Let $\mathbf{x} = (x_1, \dots, x_n)$ be a realization of $\mathbf{X} = (X_1, \dots, X_n)$
- log-likelihood function:

$$l(a; \mathbf{x}) = -n \log(2a) + \sum_{i=1}^n \log \left(F \left(\frac{x_i + a}{\sigma} \right) - F \left(\frac{x_i - a}{\sigma} \right) \right)$$

- ML estimator of a

$$\hat{a}_{ML} = \arg \max_{a \in (0, \infty)} l(a; \mathbf{x})$$

Some examples of error

- Normal error; $\varepsilon \sim \mathcal{N}(0, 1)$; $f_\varepsilon(x) = \frac{1}{\sqrt{2\pi}}e^{-x^2/2}$
 - corresponding ML estimator of a is CAE
 - classical regularity conditions
 - sensitive to outliers
- Laplace error; $\varepsilon \sim \mathcal{L}(0, \sqrt{2}/2)$; $f_\varepsilon(x) = \frac{\sqrt{2}}{2}e^{-2|x|/\sqrt{2}}$
 - corresponding ML estimator of a is CAE
 - nonstandard regularity conditions
 - more robust

- So, in both cases

$$\sqrt{n}(\hat{a}_{ML} - a_0) \longrightarrow \mathcal{N}\left(0, \frac{1}{I(a_0)}\right)$$

- where

$$I(a) = \frac{-1}{a^2} + \frac{1}{a\sigma^2} \int_0^\infty \frac{\left(f\left(\frac{x+a}{\sigma}\right) + f\left(\frac{x-a}{\sigma}\right)\right)^2}{F\left(\frac{x+a}{\sigma}\right) - F\left(\frac{x-a}{\sigma}\right)} dx$$

- We can construct confidence intervals and tests

- Approximate confidence intervals (CI) derived from asymptotic distribution of \hat{a}_{ML} :

$$\left(\hat{a}_{ML} - \frac{z_{\alpha/2}}{\sqrt{nI(\hat{a}_{ML})}}, \hat{a}_{ML} + \frac{z_{\alpha/2}}{\sqrt{nI(\hat{a}_{ML})}} \right)$$

- Likelihood ratio (LR) based confidence intervals:

$$\lambda(\mathbf{X}) = \frac{\sup_{a_0} L(a; \mathbf{X})}{\sup_{(0, \infty)} L(a; \mathbf{X})} = \frac{L(a_0; \mathbf{X})}{L(\hat{a}_{ML}; \mathbf{X})}$$

- Under a_0 (the true value of a):

$$-2 \log \lambda(\mathbf{X}) \xrightarrow{D} \chi_1^2$$

- LR.CI is the set:

$$\{a \mid l(\hat{a}_{ML}) - l(a) \leq 0.5 \chi_1^2(1 - \alpha)\}$$

- For testing $H_0 : a = a_0$ against $H_1 : a \neq a_0$, critical regions:

- AD (Wald) approach $\left\{ \mathbf{x} \mid \sqrt{nI(a_0)}|\hat{a}_{ML} - a_0| \geq z_{\alpha/2} \right\}$ or

$$\left\{ \mathbf{x} \mid \chi_W^2 := nI(a_0) (\hat{a}_{ML} - a_0)^2 \geq \chi_1^2(1 - \alpha) \right\}$$

- LR approach

$$\left\{ \mathbf{x} \mid \chi_L^2 := -2 \log \lambda(\mathbf{x}) \geq \chi_1^2(1 - \alpha) \right\}$$

- Approximate power

$$\beta(a) = 1 - F(\chi_1^2(1 - \alpha))$$

- $F(x)$ is the cdf of non-central χ^2 distribution with 1 df and ncp $nI(a_0)(a - a_0)^2$

$$X = U + \sigma\varepsilon, U \sim \mathcal{U}[-a, a], a > 0, \sigma > 0$$

$$f_U(x) = \frac{1}{2a}I_{[-a,a]}(x),$$

- We have conditions on error PDF for the MLE to be CAE
- Examples of errors with which the model is regular
 - normal error
 - logistic error
 - student t error
- student t error - more robust model

- LeArEst: Border and Area Estimation of Data Measured with Additive Error
- available on CRAN:
<https://cran.r-project.org/package=LeArEst>
- estimation of the uniform support from the contaminated data
- constructing CI and tests
- area estimation of an elliptical object